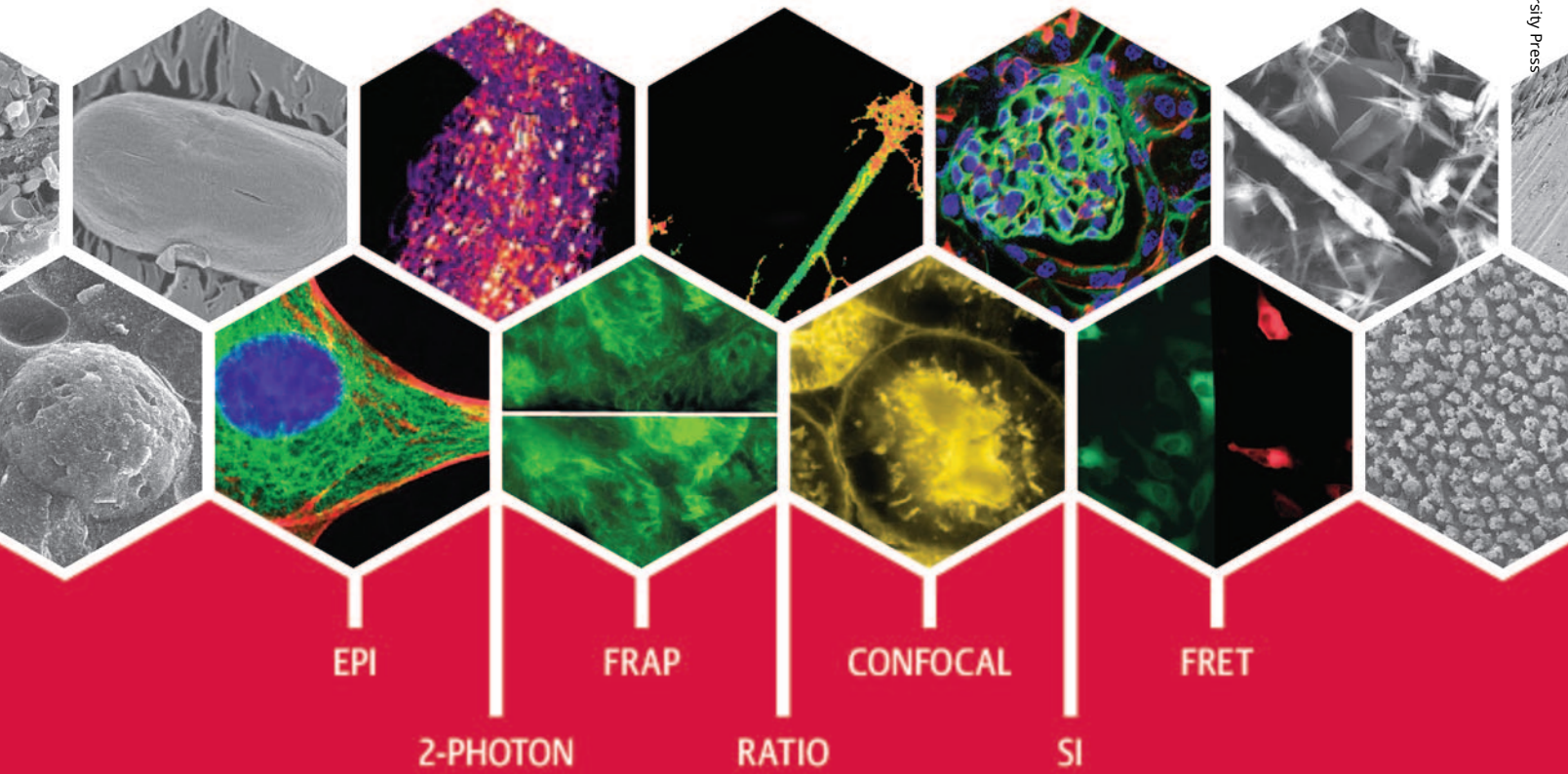




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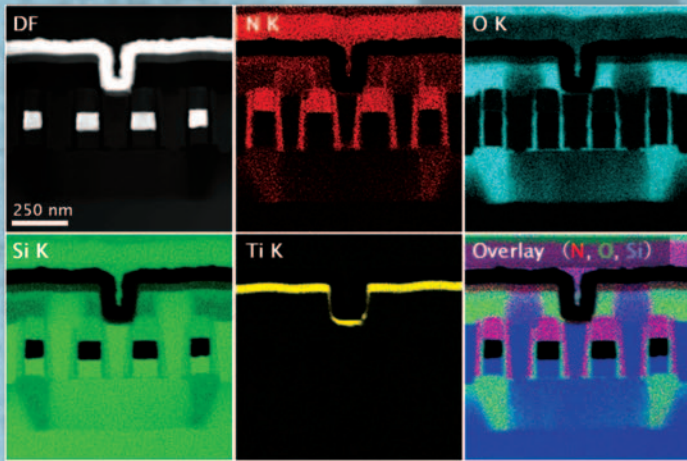
0.98sr 100mm²

- Exponentially enhances elemental mapping for nano-area analysis TEM
- Automatic retractable design



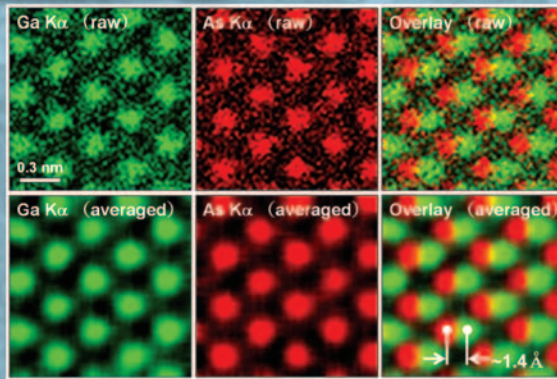
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